UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
UNITED STATES PATENT AND TRADEMARK OFFICE
WASHINGTON, D.C. 20231
www.uspto.gov

Sb Data Sheet

CONFIRMATION NO. 8779

SERIAL NUMBER 09/891,511	FILING DATE 06/27/2001 RULE	CLASS 438	GROUP ART UNIT 2812	ATTORNEY DOCKET NO. 010819

APPLICANTS

Mamoru Nakasuji, Kanagawa, JAPAN;
Nobuharu Noji, Kanagawa, JAPAN;
Tohru Satake, Kanagawa, JAPAN;
Masahiro Hatakeyama, Kanagawa, JAPAN;
Toshifumi Kimba, Kanagawa, JAPAN;
Hirosi Sobukawa, Kanagawa, JAPAN;
Shoji Yoshikawa, Tokyo, JAPAN;
Takeshi Murakami, Tokyo, JAPAN;
Kenji Watanabe, Kanagawa, JAPAN;
Tsutomu Karimata, Kanagawa, JAPAN;
Shin Oowada, Kanagawa, JAPAN;
Mutsumi Saito, Kanagawa, JAPAN;
Yuichiro Yamazaki, Tokyo, JAPAN;
Takamitsu Nagai, Kanagawa, JAPAN;
Ichirota Nagahama, Kanagawa, JAPAN;

** CONTINUING DATA ••••••••••••••••••••••••••
none

** FOREIGN APPLICATIONS ••••••••••••••••••••
JAPAN 2000-193104 08/27/2000
JAPAN 2000-229101 07/28/2000
JAPAN 2000-335934 11/02/2000
JAPAN 2001-11218 01/19/2001
JAPAN 2001-31901 02/08/2001
JAPAN 2001-31906 02/08/2001
JAPAN 2001-33599 02/09/2001
JAPAN 2001-35089 02/13/2001
JAPAN 2001-158662 05/28/2001
JAPAN 2001-162041 05/30/2001
JAPAN 2001-189304 06/22/2001

IF REQUIRED, FOREIGN FILING LICENSE GRANTED
** 08/28/2001

Foreign Priority claimed ☑ yes ☐ no 35 USC 119 (a-d) conditions ☑ yes ☐ no ☐ Met after met Verified and Acknowledged Examiner's Signature		STATE OR COUNTRY JAPAN	SHEETS DRAWING 50	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 13

ADDRESS
23850

TITLE
Inspection system by charged particle beam and method of manufacturing devices using the system